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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE		ATTY DOCKET NO. 0557-4956-3		SERIAL NO. 09/544,289	
LIST OF	REFE	RENCES CITED BY AF		APPLICANT Takayı	uki HIYC	)SHI	
			FILING DATE April 6, 2000		GROUP 2753 2861		
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
48	AA	4,376,282	03/08/83	S. KOTANI, et al.	347	244	
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		DOCUMENT NUMBER	DATE	COUNTRY		YES	
<b>67</b>	AO	61-94775	05/13/86	<u> </u>		<del> </del>	X
<b>19</b> 0	AP	30 31 295 A1	03/26/81				X
48	AQ	63-112172	05/17/88	JAPAN (with English Abstract)		<u> </u>	X
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	<del></del>	OTHER R	EFERENCES (	Including Author, Title, Date, Pertinen	t Pages, e	tc.)	
	AW						
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Examiner		schi Phan			Date Considered 2/6/24		
*Examiner: In: conformance	itial if re	eference is considered, of considered, include c	, whether or not copy of this form	t citation is in conformance with MPEP 60 with next communication to applicant.	ວອ; Draw ແ	ne through	citation if not in